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## MAX77752

## Multichannel Integrated Power Management IC

### General Description

The MAX77752 is a highly-integrated power management solution including three step-down converters, a low-dropout linear regulator, two external regulators enable outputs, two dedicated load switch controllers, and an inrush-current limiter which can be configured as a third load switch controller using OTP. The MAX77752 provides a combination of high-performance power management components, high-accuracy monitoring, and a customized top-level controller that results in an efficient, size optimized solution.

The 40-pin, 5mm x 5mm x 0.8mm, 0.4mm pitch TQFN package is ideal for space constrained applications.

Numerous factory programmable options allow the device to be tailored for many variations of the end application.

### Applications

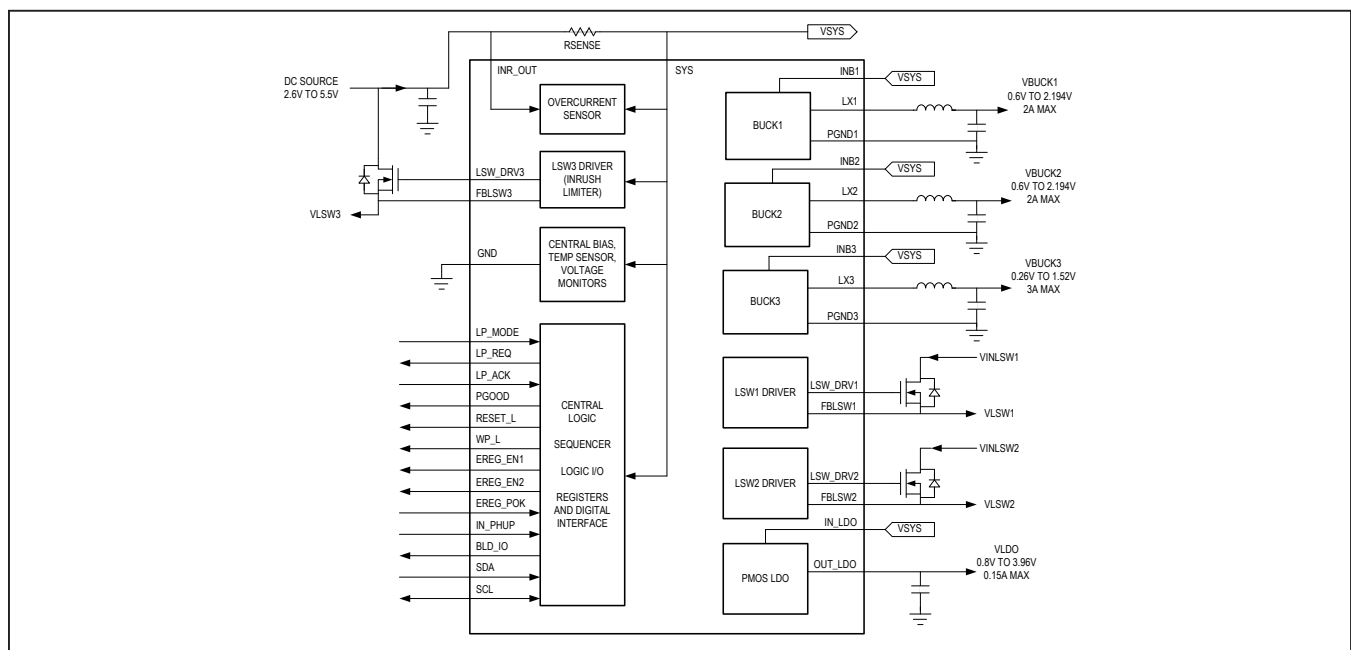
- Solid-State Drive Systems
- Handheld Devices
- Gaming Consoles
- Drones
- Automation Systems
- Cameras

### Benefits and Features

- Highly Integrated
  - Three Buck Regulators
    - Integrated High-Accuracy Brownout Comparators
  - One Low-Dropout Linear Regulator
    - Low-Input Voltage
  - Two Dedicated Load Switch Controllers
  - One Inrush-Current Limiter, Configurable to be Load Switch 3 Controller Using OTP
  - Two External Regulator Enable Outputs
  - Voltage Monitor for Backup Power Control
- Highly Flexible and Configurable
  - I<sup>2</sup>C-Compatible Interface
  - Factory OTP Options Available
  - Flexible Power Sequencer
  - Configurable Sleep-State Control
- Small Size
  - 40-Pin, 5mm x 5mm x 0.8mm, 0.4mm Pitch TQFN
  - 70mm<sup>2</sup> Total Solution Size

*Ordering Information* appears at end of data sheet.

### Simplified Block Diagram



## Absolute Maximum Ratings

### Top

IN_DRV to GND	-0.3V to +16.0V
IN_SNS to GND (Note 1)	-0.3V to +6.0V
INR_OUT to GND	-0.3V to +6.0V
SYS to GND	-0.3V to +6.0V
IN_PHUP to GND	-0.3V to +6.0V
RESET_L to GND	-0.3V to $V_{SYS}+0.3V$
LP_REQ to GND	-0.3V to $V_{SYS}+0.3V$
LP_ACK to GND	-0.3V to $V_{SYS}+0.3V$
LP_MODE to GND	-0.3V to $V_{SYS}+0.3V$
WP_L to GND (Note 2)	-0.3V to $V_{H\_INT}$
PGOOD to GND (Note 2)	-0.3V to $V_{H\_INT}$
EREG_EN1 to GND (Note 2)	-0.3V to $V_{H\_INT}$
EREG_EN2 to GND	-0.3V to 6.0V
EREG_POK to GND	-0.3V to $V_{SYS}+0.3V$
BLD_IO to GND (Note 2)	-0.3V to +6.0V
WP_L Sink Current	35mA
RESET_L Sink Current	35mA
PGOOD Sink Current	35mA
EREG_EN1 Sink Current	35mA
EREG_EN2 Sink Current	35mA
LP_REQ Sink Current	35mA
DGND to GND	-0.3V to +0.3V

### LDO

IN_LDO to GND	-0.3V to +6.0V
OUT_LDO to GND	-0.3V to $V_{IN\_LDO}+0.3V$

### Buck

INB1, INB2, INB3 to SYS	-0.3V to +0.3V
INB1 to PGND1	-0.3V to +6.0V
INB2 to PGND2	-0.3V to +6.0V
INB3 to PGND3	-0.3V to +6.0V
LX1 to PGND1 (Note 3)	-0.3V to $V_{INB1}+0.3V$
LX2 to PGND2 (Note 3)	-0.3V to $V_{INB2}+0.3V$
LX3 to PGND3 (Note 3)	-0.3V to $V_{INB3}+0.3V$
LX1, LX2 RMS Current per pin ( $T_J = +110^\circ C$ )	
(RMS current per pin ( $T_J = +110^\circ C$ ))	1.7A
LX3 RMS Current per pin ( $T_J = +110^\circ C$ )	
(RMS current per pin ( $T_J = +110^\circ C$ ))	3.0A
FBB1, FBB2, FBB3 to GND	-0.3V to $V_{SYS}+0.3V$
PGND1, PGND2, PGND3 to GND	-0.3V to +0.3V

### I<sup>2</sup>C

SDA, SCL to GND	-0.3V to $V_{IN\_VIO\_I2C}+0.3V$
SDA Sink Current	35mA

### Load Switch

LSW_DRV1 to GND	-0.3V to +16.0V
LSW_DRV2 to GND	-0.3V to +16.0V
FBLSW1 to GND	-0.3V to $V_{SYS}+0.3V$
FBLSW2 to GND	-0.3V to $V_{SYS}+0.3V$

### Continuous Power Dissipation (Multilayer Board)

$T_A = +70^\circ C$ , derate 35.70mW/ $^\circ C$	
above $+70^\circ C$	mW to 2857.1mW
Operating Temperature Range	$-40^\circ C$ to $+85^\circ C$
Junction Temperature	$+150^\circ C$
Storage Temperature Range	$-40^\circ C$ to $+150^\circ C$
Soldering Temperature (reflow)	$+260^\circ C$

**Note 1:** IN\_SNS voltage ramp rates greater than 2.8V/ $\mu s$  trigger the internal ESD device and should be avoided. The ESD device recovers if exposed to an excessive ramp rate.

**Note 2:**  $V_{H\_INT}$  is the maximum voltage of  $V_{SYS}$  and  $V_{IN\_PHUP}$ .

**Note 3:** The specified voltage limitation is for steady state conditions. Dead times of a few nano seconds exist during the dynamic BUCK regulator transitions from inductor charging to inductor discharging and vice versa. These dead times allow internal clamping diodes to PGNDx and INBx to forward bias ( $V_f \sim 1V$ ). When the LXx waveform is observed on a high-bandwidth oscilloscope ( $\geq 100MHz$ ), the LXx transition edges are commonly seen with 1.5V spikes. These spikes are due to (1) the internal clamping diode forward voltage and (2) the high rate of current change through the current loop's inductance ( $V = L \times di/dt$ ). Designs must follow the recommended printed circuit board (PCB) layout in order to minimize this current loop's inductance.

*Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.*



## Package Information

### TQFN

<b>PACKAGE CODE</b>	<b>T4055+1C</b>
Outline Number	<a href="#">21-0140</a>
Land Pattern Number	<a href="#">90-0016</a>
<b>Thermal Resistance, Single-Layer Board:</b>	
Junction to Ambient ( $\theta_{JA}$ )	45°C/W
Junction to Case ( $\theta_{JC}$ )	2°C/W
<b>Thermal Resistance, Four-Layer Board:</b>	
Junction to Ambient ( $\theta_{JA}$ )	28°C/W
Junction to Case ( $\theta_{JC}$ )	2°C/W

For the latest package outline information and land patterns (footprints), go to [www.maximintegrated.com/packages](http://www.maximintegrated.com/packages). Note that a “+”, “#”, or “-” in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status.

Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a four-layer board. For detailed information on package thermal considerations, refer to [www.maximintegrated.com/thermal-tutorial](http://www.maximintegrated.com/thermal-tutorial).

## Electrical Characteristics—Global Resources

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>SUPPLY CURRENT</b>						
OFF State Quiescent Current	$I_{QSYS\_OFF}$	$V_{SYSUVLO} < V_{SYS} < V_{SYS\_RESET}$ (rising), $OTP\_INT\_PU = 1$ , all regulators are disabled. This includes any central bias currents disabled (EREG_EN1 pulled to $V_{SYS}$ )		86	135	$\mu A$
DEVSLP State Quiescent Current	$I_{QSYS\_DEVSLP}$	$V_{SYS} = 3.3V$ , $V_{SYS} > V_{SYS\_RESET}$ , $OTP\_INT\_PU = 0$ , PMIC in DEVSLP State, Buck2, Buck3, LDO enabled in low-power mode. No load on all regulators. All other regulators disabled		70	125	$\mu A$
		$V_{SYS} = 5V$ , $V_{SYS} > V_{SYS\_RESET}$ , $OTP\_INT\_PU = 0$ , PMIC in DEVSLP state, Buck2, Buck3, LDO enabled in low-power mode. No load on all regulators. All other regulators disabled		90	155	
Buck Quiescent Supply Current	$I_{QSYS\_BUCK}$	$V_{SYS} = 5V$ , $V_{SYS} > V_{SYS\_RESET}$ , all bucks enabled in normal-power mode and skip mode		233	420	$\mu A$

### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>BIAS AND REFERENCE CURRENT GENERATOR</b>						
Operating Voltage Range	$V_{SYS}$		2.6		5.5	V
Quiescent Supply Current	$I_{QCBRG}$	$V_{SYS} > V_{SYSUVLO}$ (rising)		25		$\mu A$
Shutdown Supply Current		$V_{SYS} < V_{SYSUVLO}$ (falling)		0.1		$\mu A$
Bias Enable time	$t_{BIASOK}$			100		$\mu s$
<b>POR COMPARATOR (INTERNAL)</b>						
Quiescent Supply Current	$I_{QSYS\_POR}$			1		$\mu A$
POR Undervoltage-Lockout Threshold	$V_{POR}$	$V_{SYS}$ falling		1.33		V
POR Threshold Hysteresis	$V_{HYS\_POR}$	$V_{SYS}$ rising		160		mV
Response Time		100mV overdrive		300		$\mu s$
POR to UVLO Delay	$t_{PORUVLO}$	$V_{SYS}$ rising across POR (1V to 2V)		100		$\mu s$
		$V_{SYS}$ falling across POR		50		
<b>SYS UNDERVOLTAGE-LOCKOUT COMPARATOR</b>						
Quiescent Supply Current	$I_{QSYS\_UVLO}$			1		$\mu A$
SYS Undervoltage-Lockout Threshold	$V_{SYSUVLO}$	$V_{SYS}$ falling	2.00	2.10	2.25	V
SYS Undervoltage-Lockout Hysteresis	$V_{INUVLO\_HYS}$			400		mV
SYS Undervoltage-Lockout Response Time	$t_{SYSUVLO}$	100mV overdrive, falling edge		150		$\mu s$
<b>SYS RESET COMPARATOR</b>						
Quiescent Supply Current	$I_{QSYS\_RESET}$			3		$\mu A$
Reset Falling Threshold Range	$V_{SYS\_RESET}$	Programmed by SYSRST[3:0]	2650		4150	mV
Reset Threshold Step Size				100		mV
Reset Threshold Hysteresis Range	$V_{SYSRESET\_HYS}$	Programmed by SYSRSTHYS[1:0]	150		300	mV
Reset Threshold Hysteresis Step Size				50		mV
Reset Comparator Response Time	$t_{SYSRESET}$			5		$\mu s$
Reset Comparator Accuracy		SYSRSTTH[3:0] = 0x0, 0x1, 0x5, 0xA, 0xF	-2.5		+2.5	%

### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>SYS BROWNOUT COMPARATOR</b>						
Brownout Falling Threshold Range	$V_{SYS\_BO}$	Programmed by SYSBOTH[3:0]	2800		4300	mV
Brownout Threshold Step Size				100		mV
Brownout Threshold Hysteresis Range	$V_{SYS\_BO\_HYS}$	Programmed by SYSBOHYS[1:0]	150		300	mV
Brownout Threshold Hysteresis Step Size				50		mV
Brownout Comparator Response Time	$t_{SYSBO}$	SYS_BO_PR[1:0] = 0b00 (fast), PMIC not in DEVSLP state, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s		1.04		$\mu$ s
		SYS_BO_PR[1:0] = 0b01 (med-fast), PMIC not in DEVSLP state, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s		1.14		
		SYS_BO_PR[1:0] = 0b10 (med-slow), PMIC not in DEVSLP state, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s		1.30		
		SYS_BO_PR[1:0] = 0b11 (slow), PMIC not in DEVSLP state, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s		1.68		
Brownout Comparator Response Time (DEVSLP)	$t_{SYSBO}$	PMIC in DEVSLP state, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s		3.53		$\mu$ s
Quiescent Supply Current	$I_{QSYS\_BO}$	SYS_BO_PR[1:0] = 0b00 (fast), PMIC not in DEVSLP state		13.4		$\mu$ A
		SYS_BO_PR[1:0] = 0b01 (med-fast), PMIC not in DEVSLP state		10.4		
		SYS_BO_PR[1:0] = 0b10 (med-slow), PMIC not in DEVSLP state		7.4		
		SYS_BO_PR[1:0] = 0b11 (slow), PMIC not in DEVSLP state		4.4		
Quiescent Supply Current (DEVSLP)	$I_{QSYS\_BO}$	PMIC in DEVSLP state		1.3		$\mu$ A
Brownout Comparator Accuracy		SYSBO[3:0] = 0x0, 0x1, 0x5, 0xA, 0xF, PMIC is not in DEVSLP state	-2.5		+2.5	%
Brownout Comparator Accuracy (DEVSLP)		SYSBO[3:0] = 0x0, 0x1, 0x5, 0xA, 0xF, PMIC is in DEVSLP state	-2.5		+2.5	%
Brownout Timer Period	$t_{BO}$	T_BO_EN = 1		100		ms

### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>OSCILLATOR</b>						
Clock Frequency	CLK32K	$V_{SYS} = 5V$		31.5		kHz
Oscillator Tolerance		$V_{SYS} = 3.3V$	-10		+10	%
		$V_{SYS} = 5V$	-10		+10	
<b>WP_L OUTPUT (OPEN DRAIN)</b>						
WP_L Output-Voltage Low	$V_{OL}$	$I_{SINK} = 2mA$			0.4	V
WP_L Open Leakage Current		$V_{SYS} = V_{WP\_L} = 5.5V$ , $T_A = +25^{\circ}C$ , OTP_INT_PU[0] = 0b0		0.001	1	$\mu A$
		$V_{SYS} = V_{WP\_L} = 5.5V$ , $T_A = +85^{\circ}C$ , OTP_INT_PU[0] = 0b0		0.01		
WP_L Falling Edge Time		$C_{WP\_L} = 25pF$ , $V_{WP\_L} = 1.8V \geq 0$		25		ns
WP_L Output Deassert Delay Time	$t_{WPDLY}$	WP_L_DLY[1:0] = 0b00 (based on an internal 31.5kHz clock)		0		$\mu s$
		WP_L_DLY[1:0] = 0b01 (based on an internal 31.5kHz clock)		254		
		WP_L_DLY[1:0] = 0b10 (based on an internal 31.5kHz clock)		508		
		WP_L_DLY[1:0] = 0b11 (based on an internal 31.5kHz clock)		1016		
WP_L Output Assert Delay Time				0		$\mu s$
WP_L Pullup Resistance	$R_{PU\_WP\_L}$	Pulled up to $V_{IN\_VIO}$ , OTP_INT_PU[0] = 0b1	50	100	170	k $\Omega$
<b>RESET_L OUTPUT (OPEN DRAIN)</b>						
RESET_L Output-Voltage Low	$V_{OL}$	$I_{SINK} = 2mA$			0.4	V
RESET_L Open Leakage Current		$V_{SYS} = V_{RESET\_L} = 5.5V$ , $T_A = +25^{\circ}C$ , OTP_INT_PU[0] = 0b0		0.001	1	$\mu A$
		$V_{SYS} = V_{RESET\_L} = 5.5V$ , $T_A = +85^{\circ}C$ , OTP_INT_PU[0] = 0b0		0.01		
RESET_L Falling Edge Time		$C_{RESET\_L} = 25pF$ , $V_{RESET\_L}$ falling from $1.8V \geq 0$		25		ns

### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
RESET_L Output Deassert Delay Time	$t_{RSTDLY}$	RST_L_DLY[1:0] = 0b00 (based on an internal 31.5kHz clock)		0		$\mu s$
		RST_L_DLY[1:0] = 0b01 (based on an internal 31.5kHz clock)		254		
		RST_L_DLY[1:0] = 0b10 (based on an internal 31.5kHz clock)		508		
		RST_L_DLY[1:0] = 0b11 (based on an internal 31.5kHz clock)		1016		
RESET_L Output Assert Delay Time				0		$\mu s$
RESET_L Pullup Resistance	$R_{PU\_RESET\_L}$	Pulled up to $V_{IN\_VIO}$ , OTP_INT_PU[0] = 0b1	50	100	170	$k\Omega$
<b>PGOOD OUTPUT (OPEN DRAIN)</b>						
PGOOD Output-Voltage Low	$V_{OL}$	$I_{SINK} = 2mA$			0.4	V
PGOOD Open Leakage Current		$V_{SYS} = V_{PGOOD} = 5.5V$ , $T_A = +25^{\circ}C$ , OTP_INT_PU[0] = 0b0		0.001	1	$\mu A$
		$V_{SYS} = V_{PGOOD} = 5.5V$ , $T_A = +85^{\circ}C$ , OTP_INT_PU[0] = 0b0		0.01		
PGOOD Falling Edge Time		$C_{PGOOD} = 25pF$ , $V_{PGOOD} = 1.8V \geq 0$		25		ns
PGOOD Output Assert Delay Time	$t_{PGOODDLY}$	PG_DLY[1:0] = 0b00 (based on an internal 31.5kHz clock)		31.5		$\mu s$
		PG_DLY[1:0] = 0b01 (based on an internal 31.5kHz clock)		254		
		PG_DLY[1:0] = 0b10 (based on an internal 31.5kHz clock)		508		
		PG_DLY[1:0] = 0b11 (based on an internal 31.5kHz clock)		1016		
PGOOD Output Deassert Delay Time				0		$\mu s$
PGOOD Pullup Resistance	$R_{PU\_PGOOD}$	Pulled up to $V_{IN\_VIO}$ . OTP_INT_PU[0] = 0b1	50	100	170	$k\Omega$



### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>LP_MODE INPUT</b>						
LP_MODE I/O Pad Operating Voltage	$V_{SYS}$		2.6		5.5	V
LP_MODE Input-Low Voltage	$V_{IL}$				0.4	V
LP_MODE Input-High Voltage	$V_{IH}$		1.4			V
LP_MODE Input Hysteresis	$V_{HYS}$			50		mV
LP_MODE Input Leakage Current		$V_{SYS} = V_{IN\_VIO} = 5.5V$ , $V_{LP\_MODE} = 0V$ and $5.5V$ , $T_A = +25^{\circ}C$		0.001	1	$\mu A$
		$V_{SYS} = V_{IN\_VIO} = 5.5V$ , $V_{LP\_MODE} = 0V$ and $5.5V$ , $T_A = +85^{\circ}C$		0.01		
LP_MODE Debounce	$t_{LPMD\_DBNC}$	Debounce applies to rising and falling edge. Does not account for oscillator tolerance (Note 4)		95	127	$\mu s$
LP_MODE I/O Pad Undervoltage Lockout	$V_{SYSUVLO}$	$V_{SYS}$ falling		2.1		V
LP_MODE Mask Deassertion Timer	$t_{LPMD\_MSK}$		16	20	25	ms
<b>LP_ACK INPUT</b>						
I/O Pad Operating Voltage	$V_{SYS}$		2.6		5.5	V
Input Low Voltage	$V_{IL}$				0.4	V
Input High Voltage	$V_{IH}$		1.4			V
Input Hysteresis	$V_{HYS}$			50		mV
Input Leakage Current		$V_{SYS} = 5.5V$ , $V_{LP\_ACK} = 0V$ and $5.5V$ , $T_A = +25^{\circ}C$ , $OTP\_INT\_PU[0] = 0b0$		0.001	1	$\mu A$
		$V_{SYS} = 5.5V$ , $V_{LP\_ACK} = 0V$ and $5.5V$ , $T_A = +85^{\circ}C$ , $OTP\_INT\_PU[0] = 0b0$		0.01		
LP_ACK Pullup Resistance	$R_{PU\_LP\_ACK}$	Pulled up to $V_{IN\_VIO}$ , $OTP\_INT\_PU[0] = 0b1$	50	100	170	k $\Omega$

### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^\circ C$  to  $+85^\circ C$ , limits are 100% tested at  $T_A = +25^\circ C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>LP_REQ OUTPUT (OPEN DRAIN)</b>						
LP_REQ Output Voltage Low	$V_{OL}$	$I_{SINK} = 2mA$			0.4	V
LP_REQ Open Leakage Current		$V_{SYS} = V_{LP\_REQ} = 5.5V$ , $T_A = +25^\circ C$ , OTP_INT_PU[0] = 0b0		0.001	1	$\mu A$
		$V_{SYS} = V_{LP\_REQ} = 5.5V$ , $T_A = +85^\circ C$ , OTP_INT_PU[0] = 0b0		0.01		
LP_REQ Falling Edge Time		$C_{LP\_REQ} = 25pF$ , $V_{LP\_REQ} = 1.8V \geq 0$		25		ns
LP_REQ Delay	$t_{LPREQ\_LOW}$	LP_REQ_T_EN = 0, PMIC in master mode (OTP_SLP_MSTRSLV = 0), applies during DevSlp exit sequence		31.75		$\mu s$
		LP_REQ_T_EN = 1, PMIC in master mode (OTP_SLP_MSTRSLV = 0), applies during DevSlp exit sequence		20		ms
LP_REQ Pullup Resistance	$R_{PU\_LP\_REQ}$	Pulled up to $V_{IN\_VIO}$ , OTP_INT_PU[0] = 0b1	50	100	170	k $\Omega$
<b>EREG_ENx OUTPUT (OPEN DRAIN)</b>						
EREG_EN1 Output-Voltage Low	$V_{OL}$	$I_{SINK} = 2mA$			0.4	V
EREG_EN2 Output-Voltage Low	$V_{OL}$	$I_{SINK} = 10mA$			0.4	V
EREG_ENx Open Leakage Current		$V_{SYS} = V_{EREG\_ENx} = 5.5V$ , $T_A = +25^\circ C$ , OTP_INT_PU[0] = 0b0		0.001	1	$\mu A$
		$V_{SYS} = V_{EREG\_ENx} = 5.5V$ , $T_A = +85^\circ C$ , OTP_INT_PU[0] = 0b0		0.01		
EREG_ENx Falling Edge Time		$C_{EREG\_ENx} = 25pF$ , $V_{EREG\_ENx} = 1.8V \geq 0$		25		ns
EREG_EN1 Pullup Resistance	$R_{PU\_EREG\_ENx}$	Pulled up to $V_{H\_INT}$ , OTP_INT_PU[0] = 0b1	50	100	170	k $\Omega$
EREG_EN2 Pullup Resistance	$R_{PU\_EREG\_ENx}$	Pulled up to $V_{IN\_VIO}$ , OTP_INT_PU[0] = 0b1	50	100	170	k $\Omega$
<b>EREG_POK INPUT</b>						
I/O Pad Operating Voltage	$V_{SYS}$		2.6		5.5	V
Input Low Voltage	$V_{IL}$				0.4	V
Input High Voltage	$V_{IH}$		1.4			V
Input Hysteresis	$V_{HYS}$			50		mV

### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Input Leakage Current		$V_{SYS} = 5.5V$ , $V_{EREG\_POK} = 0V$ and $5.5V$ , $T_A = +25^{\circ}C$ , $OTP\_INT\_PU[0] = 0b0$		0.001	1	$\mu A$
		$V_{SYS} = 5.5V$ , $V_{EREG\_POK} = 0V$ and $5.5V$ , $T_A = +85^{\circ}C$ , $OTP\_INT\_PU[0] = 0b0$		0.01		
EREG_POK Pullup Resistance	$R_{PU\_EREG\_POK}$	Pulled up to $V_{IN\_VIO}$ , $OTP\_INT\_PU[0] = 0b1$	50	100	170	$k\Omega$
<b>THERMAL MONITORS</b>						
Quiescent Supply Current	$I_{QTM}$			1.5		$\mu A$
Shutdown Supply Current				0.1		$\mu A$
Thermal Overload	$T_{JOVLD}$	$T_J$ rising, $15^{\circ}C$ hysteresis		165		$^{\circ}C$
Response Time		$5^{\circ}C$ overdrive		10		$\mu s$
<b>FLEXIBLE POWER SEQUENCER</b>						
Power-Up Sequence Enable Delay	$t_{FPSDON}$	Measured from internal FPSxEN = 1 to start of sequence (based on a 31.5kHz clock)		63.492		$\mu s$
Power-Down Sequence Enable Delay	$t_{FPSDOFF}$	Measured from internal FPSxEN = 0 to start of sequence (based on a 31.5kHz clock)		95.240		$\mu s$
Flexible Power Sequencer Event Period	$t_{FPS\_PU}$ , $t_{FPS\_PD}$	$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b000$		31		$\mu s$
		$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b001$		63		
		$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b010$		127		
		$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b011$		253		
		$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b100$		508		
		$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b101$		984		
		$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b110$		1936		
		$MSTRxUPF[2:0] =$ $MSTRxDNF[2:0] = 0b111$		3904		

### Electrical Characteristics—Global Resources (continued)

( $V_{SYS} = 3.6V$ ,  $V_{IO} = 1.8V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Power-Down Sequence Delay	$t_{PD\_DLY}$	PD_DLY[1:0] = 0b00		0		ms
		PD_DLY[1:0] = 0b01		1.0		
		PD_DLY[1:0] = 0b10		1.5		
		PD_DLY[1:0] = 0b11		2.0		
<b>BLD_IO</b>						
Maximum Bleed Time	$t_{BLEED\_MAX}$			20	22	ms
Minimum Bleed Time	$t_{BLEED\_MIN}$			31.5		$\mu s$
Bleed Threshold		BLD_IO falling		90	100	mV
Bleed Resistance	$R_{BLEED}$	BLD_IO = 0.3V		20	27	$\Omega$
BLD_IO Input Leakage Current		$V_{SYS} = 5.5V$ , $V_{BLD\_IO} = 0V$ and $5.5V$ , $T_A = +85^{\circ}C$		0.01		$\mu A$
		$V_{SYS} = 5.5V$ , $V_{BLD\_IO} = 0V$ and $5.5V$ , $T_A = +25^{\circ}C$		0.001	1	
<b>ON/OFF CONTROLLER</b>						
Hiccup Counter Limit	HICCUP_CNT_LIM			7		counts
<b>IN_PHUP</b>						
Operating Voltage Range	$V_{IN\_PHUP}$		2.4		5.5	V
IN_PHUP Supply Current	$I_{IN\_PHUP}$	$V_{SYS} = V_{IN\_PHUP} = 5.5V$ , $T_A = +25^{\circ}C$		5.0		$\mu A$

**Note 4:** The LP\_MODE debounce period has a variation due to the variability associated with quantizing an asynchronous input signal. Additionally, while measuring the period from a valid LP\_MODE edge to a subsequent event, such as LP\_REQ assertion, there is one more clock cycle (CLK32K) of delay observed in a real system.

## Electrical Characteristics—Inrush Control

( $V_{IN\_SNS} = 5.0V$ , limits are 100% tested at  $T_A = +25^\circ C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	
<b>POWER SUPPLY</b>							
Supply Voltage Range	$V_{IN}$		2.1		5.5	V	
IN Undervoltage-Lockout Threshold	$V_{INUVLO}$	$V_{IN}$ rising		2.3	2.55	V	
IN Undervoltage-Lockout Hysteresis	$V_{INUVLO\_HYS}$			200		mV	
IN Undervoltage-Lockout Response Time	$t_{INUVLO}$	$V_{IN}$ rising ( $V_{IN} = V_{INUVLO} + 100mV$ )		39		$\mu s$	
IN Overvoltage-Lockout Threshold	$V_{INOVLO}$	$V_{IN}$ rising	5.70	5.87	6.10	V	
IN Overvoltage-Lockout Hysteresis	$V_{INOVLO\_HYS}$			80		mV	
IN Overvoltage-Lockout Response Time	$t_{INOVLO}$	$V_{IN}$ rising ( $V_{IN} = V_{INOVLO} + 50mV$ )		8		$\mu s$	
Leakage	$I_{LKG\_VIN\_DRV}$	$V_{IN} = 5.5V$ , $V_{IN\_DRV} = 0V$ and $11V$ , $T_A = +25^\circ C$		0.001	1	$\mu A$	
		$V_{IN} = 5.5V$ , $V_{IN\_DRV} = 0V$ and $11V$ , $T_A = +85^\circ C$		0.01			
Supply Current (Soft-Start)	$I_{Q\_IN\_SS}$	$V_{IN\_DRV} - VINR\_OUT < V_{IN\_SNS}$ (soft-start state), $OTP\_GDRV\_FREQ = 0b111$ (800kHz), $V_{IN\_SNS} = 3.3V$		85		$\mu A$	
		$V_{IN\_DRV} - VINR\_OUT < V_{IN\_SNS}$ (soft-start state), $OTP\_GDRV\_FREQ = 0b111$ (800kHz), $V_{IN\_SNS} = 5V$		138			
Supply Current (Steady-State)	$I_{IN}$	$V_{IN\_DRV} - VINR\_OUT = V_{IN\_SNS}$ (steady state), $t_{SS\_DONE}$ expired, $f_{GDRV} = 12.5kHz$ , $V_{IN\_SNS} = 3.3V$		26		$\mu A$	
		$V_{IN\_DRV} - VINR\_OUT = V_{IN\_SNS}$ (steady state), $t_{SS\_DONE}$ expired, $f_{GDRV} = 12.5kHz$ , $V_{IN\_SNS} = 5V$		37			
<b>NMOS SWITCH DRIVER</b>							
Gate Drive ON Voltage	$V_{IN\_DRV\_ON}$	$V_{IN} = 5V$	Voltage with respect to ground when external MOSFET is being driven to it's fully ON state	8.5		11	V
Gate Drive Current	$I_{GDRV\_INRUSH}$	$V_{IN} = 3.3V$ , 1X gate drive frequency setting		1.8	3.0	4.2	$\mu A$
4x Gate Drive Oscillator Frequency	$f_{GDRV\_4X}$	$OTP\_INR\_FREQ[2:0] = 0b111$ , $V_{IN} = 3.3V$ , $V_{IN} = 5V$		720			kHz



### Electrical Characteristics—Inrush Control (continued)

( $V_{IN\_SNS} = 5.0V$ , limits are 100% tested at  $T_A = +25^\circ C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
2x Gate Drive Oscillator Frequency	$f_{GDRV\_2X}$	OTP_INR_FREQ[2:0] = 0b110, $V_{IN} = 3.3V, V_{IN} = 5V$		360		kHz
1x Gate Drive Oscillator Frequency	$f_{GDRV\_1X}$	OTP_INR_FREQ[2:0] = 0b101 (nominal gate drive strength), $V_{IN} = 3.3V, V_{IN} = 5V$	120	180	240	kHz
0.5x Gate Drive Oscillator Frequency	$f_{GDRV\_0.5X}$	OTP_INR_FREQ[2:0] = 0b100, $V_{IN} = 3.3V, V_{IN} = 5V$		90		kHz
0.25x Gate Drive Oscillator Frequency	$f_{GDRV\_0.25X}$	OTP_INR_FREQ[2:0] = 0b011, $V_{IN} = 3.3V, V_{IN} = 5V$		45		kHz
0.125x Gate Drive Oscillator Frequency	$f_{GDRV\_0.125X}$	OTP_INR_FREQ[2:0] = 0b010, $V_{IN} = 3.3V, V_{IN} = 5V$	15	23	32	kHz
0.0625x Gate Drive Oscillator Frequency	$f_{GDRV\_0.0625X}$	OTP_INR_FREQ[2:0] = 0b001, $V_{IN} = 3.3V, V_{IN} = 5V$		11.25		kHz
0.03125x Gate Drive Oscillator Frequency	$f_{GDRV\_0.03125X}$	OTP_INR_FREQ[2:0] = 0b000, $V_{IN} = 3.3V, V_{IN} = 5V$		5.625		kHz
Gate Drive Discharge Resistance	$R_{GDRV\_DIS}$	Resistance from INR_DRV to INR_OUT, $V_{INR\_DRV-INR\_OUT} = 4V$		74		$\Omega$
		Resistance from INR_DRV to INR_OUT, $V_{INR\_DRV-INR\_OUT} = 3.3V$		100		
<b>TIMING</b>						
Start-Up Delay	$t_{EN\_INRUSH}$	Time from $V_{IN}$ rising above $V_{INUVLO}$ to the internal charge pump being enabled. Duration is based on the gate drive oscillator frequency ( $f_{GDRV}$ ) selected by OTP_INR_FREQ[2:0]		128		cycles of $f_{GDRV}$
Soft-Start Done Time	$t_{SS\_1}$	Duration from MOSFET drive circuit being enabled (subsequent to startup delay) to the point when the IN_SS_DONE (internal signal) is asserted allowing a power-up sequence to occur. Based on default gate drive frequency ( $f_{GDRV}$ ) selected by OTP_INR_FREQ[2:0]		512		cycles of $f_{GDRV}$
Gate Drive Idle Time	$t_{SS\_DONE}$	Duration from MOSFET drive circuit being enabled (subsequent to the startup delay) to the point when the gate drive oscillator frequency folds back to the 12.5kHz setting (idle gate drive). Based on default gate drive frequency ( $f_{GDRV}$ ) selected by OTP_INR_FREQ[2:0]		1024		cycles of $f_{GDRV}$

### Electrical Characteristics—Current Sense Amplifier

( $V_{SYS} = 3.3V$ ,  $C_{LOAD} = 10pF$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>INPUT OVERCURRENT</b>						
Input Overcurrent Threshold		2.25A setting, $V_{SYS} = 3.3V$	-6.5		+6.5	%
CSA Debounce Timer		OTP_CSA_DBNC = 0		100		$\mu s$
		OTP_CSA_DBNC = 1		50		
Overcurrent-Sense Comparator Threshold 1	$V_{OC\_THR}$	Overcurrent limit, CSTH_OPT[1:0] = 0b00		30		mV
Overcurrent-Sense Comparator Threshold 2	$V_{OC\_THR}$	Overcurrent limit, CSTH_OPT[1:0] = 0b01		35		mV
Overcurrent-Sense Comparator Threshold 3	$V_{OC\_THR}$	Overcurrent-limit, CSTH_OPT[1:0] = 0b10		40		mV
Overcurrent-Sense Comparator Threshold 4	$V_{OC\_THR}$	Overcurrent limit, CSTH_OPT[1:0] = 0b11		45		mV

### Electrical Characteristics—Buck Regulators (BUCK1/2 - 2A Output)

( $V_{SYS} = 3.6V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>SUPPLY VOLTAGE AND CURRENT</b>						
Input Voltage Range	$V_{INBx}$		2.6		5.5	V
Shutdown Supply Current	$I_{QSHDN\_BUCKx}$	(Note 5)		0.1		$\mu A$
Supply Quiescent Current	$I_{Q\_SKIP\_NM\_BUCKx}$	No switching, no load, (Note 6), $V_{SYS} = 3.3V$		19	30	$\mu A$
		No switching, no load, (Note 6), $V_{SYS} = 5V$		19	30	
	$I_{Q\_FPWM\_BUCKx}$	FPWM mode (switching at fixed frequency), no load, $V_{SYS} = 3.3V$		10		mA
		FPWM mode (switching at fixed frequency), no load, $V_{SYS} = 5V$		10		
	$I_{Q\_SKIP\_LPM\_BUCKx}$	Low-power mode (no switching), no load, (Note 6), $V_{SYS} = 3.3V$		5	9	$\mu A$
		Low-power mode (no switching), no load, (Note 6), $V_{SYS} = 5V$		5	9	

### Electrical Characteristics—Buck Regulators (BUCK1/2 - 2A Output) (continued)

( $V_{SYS} = 3.6V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>OUTPUT VOLTAGE</b>						
Output Voltage Range	$V_{OUT\_BUCKx}$	Programmable in 6.25mV steps with BUCK1VOUT[7:0] and BUCK2VOUT[7:0]	0.600		2.194	V
Output Voltage Accuracy	$V_{OUT\_ACC\_NM\_BUCKx}$	FPWM mode, normal mode, no load, $V_{OUT\_BUCK1} = 1.800V$	-2		+2	%
	$V_{OUT\_ACC\_LPM\_BUCKx}$	Low-power mode, no load, $V_{OUT\_BUCK1} = 1.800V$	-4		+4	
	$V_{OUT\_ACC\_NM\_BUCKx}$	FPWM mode, normal mode, no load, $V_{OUT\_BUCK2} = 1.200V$	-2		+2	
	$V_{OUT\_ACC\_LPM\_BUCKx}$	Low-power mode, no load, $V_{OUT\_BUCK2} = 1.200V$	-4		+4	
<b>OUTPUT CURRENT</b>						
Maximum Output Current	$I_{OUT\_MAX\_NM\_BUCKx}$	RMS, normal mode, $L = 1\mu H$	2000			mA
	$I_{OUT\_MAX\_LPM\_BUCKx}$	RMS, low-power mode, $L = 1\mu H$	10			
PMOS Peak Current Limit	$I_{LIMP}$	$V_{SYS} = 3.6V$	2300	2875	4200	mA
		$V_{SYS} = 5V$	2300	2875	4200	
NMOS Valley Current Limit	$I_{LIMV}$	$V_{SYS} = 3.6V$	2125			mA
		$V_{SYS} = 5V$	2125			
NMOS Negative Current Limit	$I_{LIMN}$	$V_{SYS} = 3.6V$	800			mA
		$V_{SYS} = 5V$	800			
<b>PERFORMANCE PARAMETERS</b>						
Line Regulation		$V_{SYS} = V_{INBx} = 2.6V$ to $5.5V$	0.2			%/V
Load Regulation		Load = 0 to 1A, FPWM mode	0.125			%/A
Load Transient Response		FPWM mode, $V_{OUT\_BUCKx} = \text{default}$ , $L = 1\mu H$ , $C_{OUT} = 12\mu F$ effective $\Delta I_{OUT} = 0.2A-2A$ , $\Delta t = 3\mu s$	88			mV
		Skip mode, $V_{OUT\_BUCKx} = \text{default}$ , $L = 1\mu H$ , $C_{OUT} = 12\mu F$ effective $\Delta I_{OUT} = 10mA$ to $0.7A$ , $\Delta t = 3\mu s$ ,	90			
Switching Frequency	$f_{SW}$	$V_{SYS} = 3.3V$	1.8	2	2.2	MHz
Dead Time	$t_{DEAD}$	$V_{SYS} = 3.3V$	2.0			ns
Switching Frequency	$f_{SW}$	$V_{SYS} = 5V$	1.8	2	2.2	MHz

### Electrical Characteristics—Buck Regulators (BUCK1/2 - 2A Output) (continued)

( $V_{SYS} = 3.6V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Dead Time	$t_{DEAD}$	$V_{SYS} = 5V$		2.0		ns
Soft-Start Slew Rate		Fixed for buck 1		6.5		mV/ $\mu$ s
		Fixed for buck 2		17		
Output Voltage Ramp-Up Slew Rate		Fixed for buckx (Notes 5, 8, 9), $C_{OUT} = 22\mu F$		40		mV/ $\mu$ s
Output Voltage Ramp-Down Slew Rate		Fixed for buck 1, 2 (Notes 5, 8), $C_{OUT} = 22\mu F$ , $BUCKxFPWMEN = 1$ ( $x = 1, 2$ ), no load		18		mV/ $\mu$ s
PMOS ON Resistance	$R_{ON\_PCH}$	$V_{SYS} = V_{INBUCKx} = 3.6V$ , $I_{OUT} = 150mA$		100	150	m $\Omega$
		$V_{SYS} = V_{INBUCKx} = 5V$ , $I_{OUT} = 150mA$		100	150	
NMOS ON Resistance	$R_{ON\_NCH}$	$V_{SYS} = V_{INBUCKx} = 3.6V$ , $I_{OUT} = 150mA$		60	100	m $\Omega$
		$V_{SYS} = V_{INBUCKx} = 5V$ , $I_{OUT} = 150mA$		60	100	
NMOS Zero-Crossing Threshold	$I_{ZX}$	Threshold to determine transition from PWM to SKIP mode		20		mA
Output Voltage Ripple in Skip Mode		$V_{OUT\_BUCKx} = 1.0V$ , $L = 1\mu H$ , $C_{OUT} = 12\mu F$ effective, no load (Note 5)		40		mV $_{P-P}$
Output Voltage Ripple in PWM Mode		$V_{OUT\_BUCKx} = 1.0V$ , $L = 1\mu H$ , $C_{OUT} = 12\mu F$ effective, $I_{LOAD} = 0.5 \times I_{OUT\_MAX\_BUCKx}$ (Note 5)		5		mV $_{P-P}$
LX Leakage	$I_{L\_LX\_25C}$	$V_{LX} = 5.5V$ or $0V$ , $T_A = +25^{\circ}C$		0.1	1	$\mu A$
	$I_{L\_LX\_85C}$	$V_{LX} = 5.5V$ or $0V$ , $T_A = +85^{\circ}C$ (Note 5)		1		
Output Active Discharge Resistance	$R_{DISCHG\_BUCKx}$	Resistance from FBBx to PGNDx, output disabled, (Note 7)		100		$\Omega$
Nominal Output Inductance	$L_{NOM}$			1.0		$\mu H$
Minimum Effective Output Capacitance	$C_{OUT\_EFF\_MIN}$	$0mA < I_{OUT} < 2000mA$	18			$\mu F$
Light Load Efficiency	$Eff_{LIGHT}$	Low-power mode, $I_{OUT} = 0.5mA$ , $V_{OUT\_BUCKx} = 1.0V$ , $L = 1\mu H$ , $DCR_L = 50m\Omega$ , $C_{OUT} = 22\mu F$ (Note 5)		75		%

### Electrical Characteristics—Buck Regulators (BUCK1/2 - 2A Output) (continued)

( $V_{SYS} = 3.6V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Typical Load Efficiency	$Eff_{IOUT\_TYP}$	$I_{OUT} = 0.25 \times I_{OUT\_MAX\_BUCKx}$ , $V_{OUT\_BUCKx} = 1.0V$ , $L = 1\mu H$ , $DCR_L = 50m\Omega$ , $C_{OUT} = 22\mu F$ (Note 5)		85		%
Maximum Load Efficiency	$EFF_{IOUT\_MAX}$	$I_{OUT} = I_{OUT\_MAX\_BUCKx}$ , $V_{OUT} = 1.0V$ , $L = 1\mu H$ , $DCR_L = 50m\Omega$ , $C_{OUT} = 22\mu F$ (Note 5)		70		%
Turn-On Delay Time	$t_{ON\_DLY\_BUCKx}$	EN signal to LX switching with bias ON		30		$\mu s$
Maximum Duty Cycle		$V_{OUT\_BUCKx} / V_{IN\_BUCKx}$ expressed as %		90		%
<b>BROWNOUT COMPARATOR</b>						
Output Brownout Threshold	$V_{BO\_BUCKx}$	Normal-power mode, falling threshold, $BUCKx\_BO\_THR[1:0] = 0b00$		75		%
		Normal-power mode, falling threshold, $BUCKx\_BO\_THR[1:0] = 0b01$		80		
		Normal-power mode, falling threshold, $BUCKx\_BO\_THR[1:0] = 0b10$		85		
		Normal-power mode, falling threshold, $BUCKx\_BO\_THR[1:0] = 0b11$		90.7		
Output Brownout Accuracy		Normal-power mode. $V_{OUT\_BUCKx} = 1.0V$ ( $V_{OUT\_BUCKx}[7:0] = 0 \times 40$ )	-4.0		+4.0	%
Output Brownout Threshold (Low-Power Mode)	$V_{BO\_BUCKx}$	Falling threshold, low-power mode		86.0		%
Output Brownout Accuracy		Low-power mode. $V_{OUT\_BUCKx} = 1.0V$ ( $V_{OUT\_BUCKx}[7:0] = 0 \times 40$ )	-4		+4	%
Output Brownout Hysteresis Range	$V_{BO\_HYS\_BUCKx}$	2-bit control over I <sup>2</sup> C. Max rising threshold limited to 96%	5		20	%
Brownout Voltage Hysteresis Programming Step Size		Programmable with $BUCKx\_BO\_HYS[1:0]$		5		%
Output Brownout Hysteresis (Low-Power Mode)	$V_{BO\_HYS\_BUCKx\_LPM}$			5		%



### Electrical Characteristics—Buck Regulators (BUCK1/2 - 2A Output) (continued)

( $V_{SYS} = 3.6V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Output Brownout Response Time	$t_{BO\_BUCKx}$	BUCKx_BO_PR[1:0] = 0b00 (fast), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.04		$\mu$ s
		BUCKx_BO_PR[1:0] = 0b01 (med-fast), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.14		
		BUCKx_BO_PR[1:0] = 0b10 (med-slow), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.30		
		BUCKx_BO_PR[1:0] = 0b11 (slow), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.68		
		Buck in low-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		3.18		
Output Brownout Supply Current	$I_{QNM\_BO\_BUCKx}$	Normal-power mode, BUCKx_BO_PR[1:0] = 0b00 (fast)		13.4		$\mu$ A
		Normal-power mode, BUCKx_BO_PR[1:0] = 0b01 (med-fast)		10.4		
		Normal-power mode, BUCKx_BO_PR[1:0] = 0b10 (med-slow)		7.4		
		Normal-power mode, BUCKx_BO_PR[1:0] = 0b11 (slow)		4.4		
	$I_{QLPM\_BO\_BUCKx}$	Low-power mode		1.3		

### Electrical Characteristics—Buck Regulators (BUCK1/2 - 2A Output) (continued)

( $V_{SYS} = 3.6V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range are guaranteed by design and characterization.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>OV COMPARATOR</b>						
Output OV Trip Level	$V_{OUTBUCKx\_OV}$	Rising edge, BUCKx_OV_THR = 1, referenced to output voltage setting		116.6		%
Output OV Hysteresis		BUCKx_OV_THR = 1		9.1		%
Output OV Trip Level	$V_{OUTBUCKx\_OV}$	Rising edge, BUCKx_OV_THR = 0, referenced to output voltage setting		108.3		%
Output OV Hysteresis		BUCKx_OV_THR = 0		2.8		%
Output OV Trip Level (Low-Power Mode)	$V_{OUTBUCKx\_OV}$	Rising edge, low-power mode		108.3		%
Output OV hysteresis (Low-Power Mode)		Low-power mode		2.8		%
Output Over-Voltage Response Time	$t_{OV\_BUCKx}$	Normal-power mode, 100mV over-drive with rising slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ rising to PGOOD pin falling (Note 5)		1.68		$\mu$ s
Output Over-Voltage Supply current	$I_{Q\_OV\_BUCKx}$	Normal-power mode		4.4		$\mu$ A
Output Over-Voltage Response Time (Low-Power Mode)	$t_{OV\_BUCKx}$	Low-power mode, 100mV over-drive with rising slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ rising to PGOOD pin falling (Note 5)		3.18		$\mu$ s
Output Over-Voltage Supply Current (Low-Power Mode)	$I_{Q\_OV\_BUCKx}$	Low-power mode		1.3		$\mu$ A

**Note 5:** Design guidance only and is not production tested.

**Note 6:** Individual buck  $I_q$  is not production tested. It is covered by a combined test by turning on all bucks.

**Note 7:** There is an n-channel MOSFET in series with the output active-discharge resistance. This NMOS requires  $V_{SYS} > 1.2V$  to be enhanced.

**Note 8:** The ramp down slew rate when the output voltage is decreased through  $I^2C$  is a function of the negative current limit and the output capacitance. With no load, forced PWM mode and 22 $\mu$ F output capacitor, the ramp-down slew rate is  $dv/dt = i / C = 0.4A / 22\mu F = 18mV/\mu s$ .

**Note 9:** DVS and soft-start ramp rates can be expected to vary by up to 30%.

### Electrical Characteristics—Buck Regulators (BUCK3 - 3A Output)

( $V_{SYS} = 5.0V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , Limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>SUPPLY VOLTAGE AND CURRENT</b>						
Input Voltage Range	$V_{INBUCK3}$		2.6		5.5	V
Shutdown Supply Current	$I_{QSHDN\_BUCK3}$	(Note 10)		0.1		$\mu A$
Supply Quiescent Current	$I_{Q\_SKIP\_NM\_BUCK3}$	No switching, no load (Note 10)		26	40	$\mu A$
	$I_{Q\_FPWM\_BUCK3}$	FPWM mode, no load (Note 10)		10		mA
	$I_{Q\_SKIP\_LPM\_BUCK3}$	Low-power mode (no switching), no load (Note 10)		10	19	$\mu A$
<b>OUTPUT VOLTAGE</b>						
Output Voltage Range	$V_{OUT\_BUCK3}$	I <sup>2</sup> C programmable in 10mV Steps (BUCK3VOUT[6:0] = 0x01 to 0x7F)	0.26		1.52	V
Output Voltage Accuracy	$V_{OUT\_ACC\_NM\_BUCK3}$	FPWM mode, normal mode, no load, $T_A = +25^{\circ}C$ , $V_{OUT\_BUCK3} = 1.0V$	-2		+2	%
	$V_{OUT\_ACC\_LPM\_BUCK3}$	Low-power mode, no load, $T_A = +25^{\circ}C$ , $V_{OUT\_BUCK3} = 1.000V$	-4		+4	
<b>PERFORMANCE PARAMETERS</b>						
Switching Frequency	$f_{SW}$	$V_{SYS} = 3.3V$	1.8	2	2.2	MHz
		$V_{SYS} = 5V$	1.8	2	2.2	
Line Regulation		$V_{INBUCK3} = 2.6V$ to $5.5V$ , $V_{OUT\_BUCK3} = 1.0V$		0.2		%/V
Load Regulation		$V_{OUT\_BUCK3} = 1.0V$ , (Note 10), load = 0 to 1A, FPWM mode		0.125		%/A
Load Transient Response (Droop)		Skip mode, $V_{OUT} =$ default, $L = 1\mu H$ , $C_{OUT} = 28\mu F$ effective $\Delta I_{OUT} = 20mA$ to $500mA$ , $\Delta t = 0.8\mu s$ (Note 10)		45		mV
		Skip mode, $V_{OUT} =$ default, $L = 1\mu H$ , $C_{OUT} = 28\mu F$ effective $\Delta I_{OUT} = 20mA$ to $3A$ , $\Delta t = 4.8\mu s$ (Note 10)		70		
Soft-Start Slew Rate		BUCK3SSRAMP = 0		2.5		mV/ $\mu s$
		BUCK3SSRAMP = 1		10		
Output Voltage Ramp-Up/Down Slew Rate (DVS)				10		mV/ $\mu s$

### Electrical Characteristics—Buck Regulators (BUCK3 - 3A Output) (continued)

( $V_{SYS} = 5.0V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , Limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
PMOS ON Resistance	$R_{ON\_PCH}$	$V_{SYS} = V_{INBUCK3} = 5V$ , $I_{OUT} = 150mA$		60	90	m $\Omega$
		$V_{SYS} = V_{INBUCK3} = 3.6V$ , $I_{OUT} = 150mA$		60	90	
NMOS ON Resistance	$R_{ON\_NCH}$	$V_{SYS} = V_{INBUCK3} = 5V$ , $I_{OUT} = 150mA$		35	60	m $\Omega$
		$V_{SYS} = V_{INBUCK3} = 3.6V$ , $I_{OUT} = 150mA$		35	60	
NMOS Zero-Crossing Threshold	$I_{ZX\_SKIP}$	SKIP mode		20		mA
	$I_{ZX\_PWM}$	PWM mode		20		
Output Voltage Ripple In Skip Mode		$V_{OUT\_BUCK3} = 1.0V$ , $L = 1\mu H$ , $C_{OUT} = 28\mu F$ effective, no load (Note 10)		15		mV
Output Voltage Ripple In PWM Mode		$V_{OUT\_BUCK3} = 1.0V$ , $L = 1\mu H$ , $C_{OUT} = 28\mu F$ effective, $I_{LOAD} = 0.5 \times I_{OUT\_MAX\_BUCK3}$ (Note 10)		5		mV
LX Leakage	$I_{L\_LX\_25C}$	$V_{LXBUCK1} = 5.5V$ or $0V$ , $T_A = +25^{\circ}C$		0.1	1	$\mu A$
	$I_{L\_LX\_85C}$	$V_{LXBUCK1} = 5.5V$ or $0V$ , $T_A = +85^{\circ}C$ (Note 10)		1		
Output Active Discharge Resistance	$R_{DISCHG\_BUCK3}$	Resistance from FBB3 to PGND3, output disabled		100		$\Omega$
Nominal Output Inductance	$L_{NOM}$			1.0		$\mu H$
Minimum Effective Output Capacitance	$C_{OUT\_EFF\_MIN}$	$0mA < I_{OUT} < 3000mA$		28		$\mu F$
Turn-On Delay Time	$t_{ON\_DLY\_BUCK1}$	EN signal to LX switching with bias ON		200		$\mu s$
Light Load Efficiency	$Eff_{LIGHT}$	Low-power mode, $I_{OUT} = 0.5mA$ , $V_{OUT\_BUCKx} = 1.0V$ , $L = 1\mu H$ , $DCR_L = 50m\Omega$ , $C_{OUT} = 3 \times 22\mu F$ (Note 10)		75		%
Typical Load Efficiency	$Eff_{I_{OUT\_TYP}}$	$I_{OUT} = 0.25 \times I_{OUT\_MAX\_BUCKx}$ , $V_{OUT\_BUCKx} = 1.0V$ , $L = 1\mu H$ , $DCR_L = 50m\Omega$ , $C_{OUT} = 3 \times 22\mu F$ (Note 10)		88		%
Maximum Load Efficiency	$Eff_{I_{OUT\_MAX}}$	$I_{OUT} = I_{OUT\_MAX\_BUCKx}$ , $V_{OUT} = 1.0V$ , $L = 1\mu H$ , $DCR_L = 50m\Omega$ , $C_{OUT} = 3 \times 22\mu F$ (Note 10)		77		%

### Electrical Characteristics—Buck Regulators (BUCK3 - 3A Output) (continued)

( $V_{SYS} = 5.0V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , Limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>OUTPUT CURRENT</b>						
Maximum Output Current	$I_{OUT\_MAX\_NM\_BUCK3}$	RMS, normal mode	3000			mA
	$I_{OUT\_MAX\_LPM\_BUCK3}$	RMS, low-power mode	10			
PMOS Peak Current Limit	$I_{LIMP}$	$T_A = -40^{\circ}C$ to $+85^{\circ}C$ , $V_{SYS} = 3.6V$	3825	4250	4675	mA
NMOS Valley Current Limit	$I_{LIMV}$		3750			mA
NMOS (Negative) Current Limit	$I_{LIMN}$		2000			mA
<b>BROWNOUT COMPARATOR</b>						
Output Brownout Threshold	$V_{BO\_BUCK3}$	Normal-power mode, falling threshold, BUCK3_BO_THR[1:0] = 0b00	77			%
		Normal-power mode, falling threshold, BUCK3_BO_THR[1:0] = 0b01	81			
		Normal-power mode, falling threshold, BUCK3_BO_THR[1:0] = 0b10	85.7			
		Normal-power mode, falling threshold, BUCK3_BO_THR[1:0] = 0b11	91			
Output Brownout Accuracy		Normal-power mode. $V_{OUT\_BUCK3} = 1.0V$ ( $V_{OUT\_BUCK3}[7:0] = 0x4B$ )	-4.5	+4.5		%
Output Brownout Threshold (Low-Power Mode)	$V_{BO\_BUCKx}$	Falling threshold, low-power mode	86.0			%
Output Brownout Accuracy		Low-power mode, $V_{OUT\_BUCK3} = 1.0V$ ( $V_{OUT\_BUCK3}[7:0] = 0x4B$ )	-4	+4		%
Output Brownout Hysteresis Range	$V_{BO\_HYS\_BUCKx}$	2-Bit control over I <sup>2</sup> C. Max rising threshold limited to 96%	5	20		%
Brownout Voltage Hysteresis Programming Step Size		Programmable with BUCKx_BO_HYS[1:0]	5			%
Output Brownout Hysteresis (Low-Power Mode)	$V_{BO\_HYS\_BUCKx\_LPM}$		5			%



### Electrical Characteristics—Buck Regulators (BUCK3 - 3A Output) (continued)

( $V_{SYS} = 5.0V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , Limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Output Brownout Response Time	$t_{BO\_BUCKx}$	BUCKx_BO_PR[1:0] = 0b00 (fast), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.04		$\mu$ s
		BUCKx_BO_PR[1:0] = 0b01 (med-fast), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.14		
		BUCKx_BO_PR[1:0] = 0b10 (med-slow), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.30		
		BUCKx_BO_PR[1:0] = 0b11 (slow), buck in normal-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		1.68		
		Buck in Low-power mode, 100mV under-drive with falling slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ falling to PGOOD pin falling		3.18		
Output Brownout Supply Current	$I_{QNM\_BO\_BUCKx}$	Normal-power mode, BUCKx_BO_PR[1:0] = 0b00 (fast)		13.4		$\mu$ A
		Normal-power mode, BUCKx_BO_PR[1:0] = 0b01 (med-fast)		10.4		
		Normal-power mode, BUCKx_BO_PR[1:0] = 0b10 (med-slow)		7.4		
		Normal-power mode, BUCKx_BO_PR[1:0] = 0b11 (slow)		4.4		
	$I_{QLPM\_BO\_BUCKx}$	Low-power mode		1.3		

### Electrical Characteristics—Buck Regulators (BUCK3 - 3A Output) (continued)

( $V_{SYS} = 5.0V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , Limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>OV COMPARATOR</b>						
Output OV Trip Level	$V_{OUTBUCK3\_OV}$	Rising edge, BUCK3_OV_THR = 1		117.1		%
Output OV hysteresis		BUCK3_OV_THR = 1		8.6		%
Output OV Trip Level	$V_{OUTBUCKx\_OV}$	Rising edge, BUCK3_OV_THR = 0		108.5		%
Output OV Hysteresis		BUCK3_OV_THR = 0		3.9		%
Output OV Trip Level (Low-Power Mode)	$V_{OUTBUCK3\_OV}$	Rising edge, low-power mode		108.3		%
Output OV Hysteresis (Low-Power Mode)		Low-power mode		3.9		%
Output Over-Voltage Response Time	$t_{OV\_BUCK3}$	Buck in normal-power mode, 100mV over-drive with rising slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCK3}$ rising to PGOOD pin falling (Note 10)		1.68		$\mu$ s
Output Over-Voltage Supply current	$I_{Q\_OV\_BUCKx}$	Buck in normal-power mode		4.4		$\mu$ A
Output Over-Voltage Response Time (Low-Power Mode)	$t_{OV\_BUCKx}$	Buck in low-power mode, 100mV over-drive with rising slew rate of 150mV/ $\mu$ s. Time from $V_{OUT\_BUCKx}$ rising to PGOOD pin falling (Note 10)		3.18		$\mu$ s
Output Over-Voltage Supply current (Low-Power Mode)	$I_{Q\_OV\_BUCK3}$	Buck in low-power mode		1.3		$\mu$ A

**Note 10:** Design guidance only and is not production tested.

## Electrical Characteristics—Load Switch Driver (LSW1/2)

( $V_{SYS} = 3.6V$ ,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ , Limits are 100% tested at  $T_A = +25^{\circ}C$ . Limits over the operating temperature range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested. x is used to represent multiple instances of similar resources, for this section  $x = 1, 2$  unless specified for e.g., LSWx represents LSW1, LSW2.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
<b>POWER SUPPLY</b>						
Supply Current	$I_{SYS\_LSW\_SS}$	$V_{INLSWx} = V_{SYS} = 5V$ , LSWxDRV_FREQ=0b111 (800kHz), $C_{OUTLSWx} = 20\mu F$		68		$\mu A$
Supply Voltage Range	$V_{SYS}$		2.6		5.5	V
Supply Current	$I_{SYS\_LSW\_SS}$	$V_{INLSWx} = V_{SYS} = 3.3V$ , LSWxDRV_FREQ = 0b111 (1.6MHz), $C_{OUTLSWx} = 20\mu F$		43		$\mu A$
		$V_{INLSWx} = V_{SYS} = 5V$ , LSWxDRV_FREQ = 0b101 (400kHz), $C_{OUTLSWx} = 20\mu F$		20		
Leakage	$I_{LKG\_LSWx\_DRV}$	$V_{SYS} = 5.5V$ , $V_{LSWx\_DRV} = 0V$ and $11V$ , $T_A = +25^{\circ}C$		0.001	1	$\mu A$
		$V_{SYS} = 5.5V$ , $V_{LSWx\_DRV} = 0V$ and $11V$ , $T_A = +85^{\circ}C$		0.01		
<b>NMOS SWITCH DRIVER</b>						
Gate Drive Voltage	$V_{LSWx\_DRV}$	$V_{SYS} = 5V$	8.5		11	V
Gate Drive Current	$I_{LSWx\_DRV}$	$V_{SYS} = 3.3V$ , 1X gate drive frequency setting (LSWx_DRV_FREQ[2:0] = 0b101), $C_{OUTLSWx} = 20\mu F$	1.85	3.7	5.55	$\mu A$
4x Gate Drive Oscillator Frequency	$f_{LSWx\_DRV\_4X}$	LSWxDRV_FREQ[2:0] = 0b111, $V_{SYS} = 3.3V$ , $V_{SYS} = 5V$		1600		kHz
2x Gate Drive Oscillator Frequency	$f_{LSWx\_DRV\_2X}$	LSWx_DRV_FREQ[2:0] = 0b110, $V_{SYS} = 3.3V$ , $V_{SYS} = 5V$		800		kHz
1x Gate Drive Oscillator Frequency	$f_{LSWx\_DRV\_1X}$	LSWx_DRV_FREQ[2:0] = 0b101 (nominal gate drive strength), $V_{SYS} = 3.3V$ , $V_{SYS} = 5V$	200	400	600	kHz
0.5x Gate Drive Oscillator Frequency	$f_{LSWx\_DRV\_0.5X}$	LSWx_DRV_FREQ[2:0] = 0b100, $V_{SYS} = 3.3V$ , $V_{SYS} = 5V$		200		kHz
0.25x Gate Drive Oscillator Frequency	$f_{LSWx\_DRV\_0.25X}$	LSWx_DRV_FREQ[2:0] = 0b011, $V_{SYS} = 3.3V$ , $V_{SYS} = 5V$		100		kHz
0.125x Gate Drive Oscillator Frequency	$f_{LSWx\_DRV\_0.125X}$	LSWx_DRV_FREQ[2:0] = 0b010, $V_{SYS} = 3.3V$ , $V_{SYS} = 5V$	25	50	75	kHz
0.0625x Gate Drive Oscillator Frequency	$f_{LSWx\_DRV\_0.0625X}$	LSWx_DRV_FREQ[2:0] = 0b001, $V_{SYS} = 3.3V$ , $V_{SYS} = 5V$		25		kHz